

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/064,881	<b>Applicant(s)/Patent under Reexamination</b> CHANG, YI-CHEN
	<b>Examiner</b> Alexander Eisen	<b>Art Unit</b> 2674

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner